# **An All-Digital CMOS Pulse-Shrinking Mechanism** for Time Measurement

**Chun-Chi Chen\* and Yan-Hsuan Huang** 

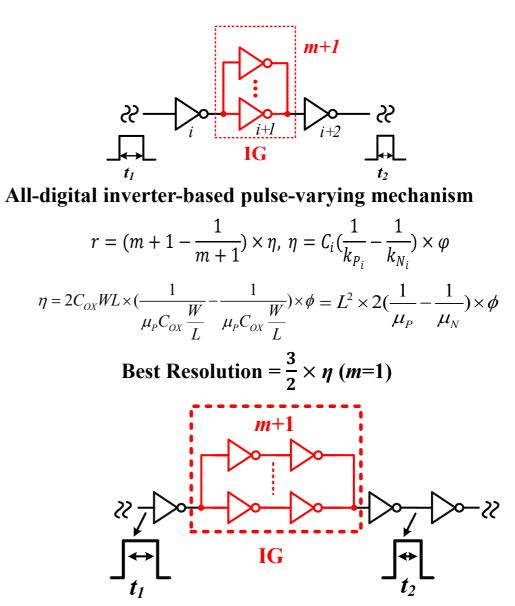
Dept. of Electronic Engineering, (First Campus), National Kaohsiung University of Science and Technology

V240014 ICICE 2024, Danang, Vietnam.

### Abstract

This paper presents a newly developed all-digital mechanism CMOS pulse-shrinking for time measurement, aimed at enhancing time resolution and improving circuit performance under process and temperature variations. In the previous alldigital mechanism, the pulse-shrinking amount (time resolution) was determined by adjusting the number of NOT gates in the inhomogeneous stage to achieve sub-gate resolution. The new mechanism introduces buffer gates to replace the original NOT gates, with the NOT gates simply added in the inhomogeneous stage to form these buffer gates. An analysis of the resolution is provided, demonstrating that the bufferbased technique effectively improves resolution compared to the inverter-based approach. The alldigital CMOS mechanism was implemented using a 0.35-µm CMOS TSMC process for performance evaluation. Simulation results show that the proposed achieves significant mechanism resolution improvement with greater stability against process and temperature variations.

### **All-Digital Mechanism**

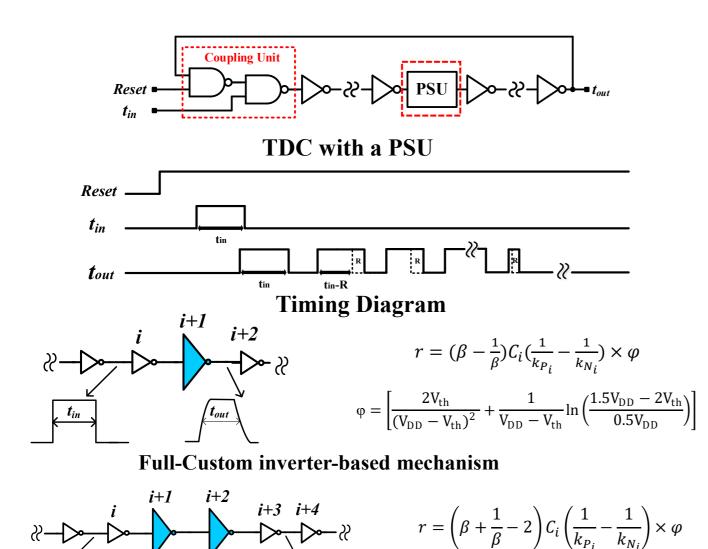


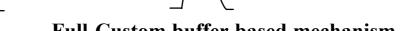
All-digital buffer-based pulse-shrinking mechanism

$$r = \left(m + 1 + \frac{1}{m+1} - 2\right) C_i \left(\frac{1}{k_{P_i}} - \frac{1}{k_{N_i}}\right) \times \varphi$$
$$= \left(\frac{m^2}{m+1}\right) C_i \left(\frac{1}{k_{P_i}} - \frac{1}{k_{N_i}}\right) \times \varphi$$

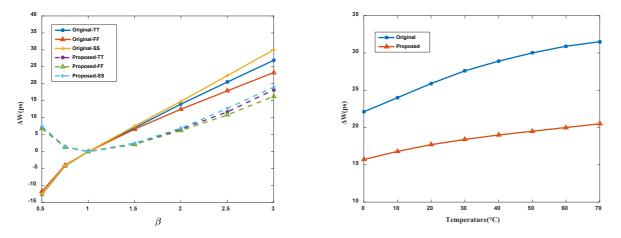
Best Resolution =  $\frac{1}{2} \times \eta$  (*m*=1)

## **Full-Custom Mechanism**



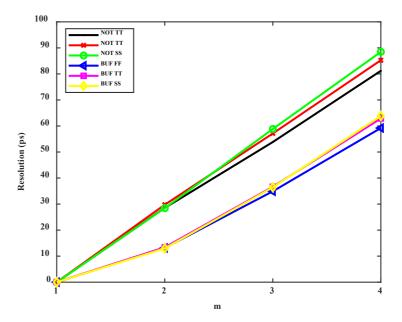


Full-Custom buffer-based mechanism

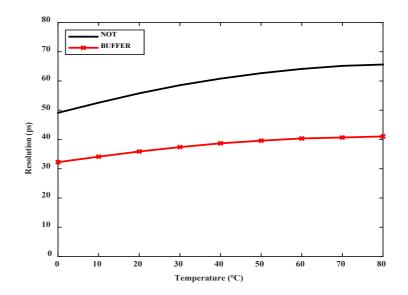


Results of the two full-custom mechanisms

## **Experimental Results**



### Simulated resolutions for different *m* value and process



#### Simulated results for temperature variation

#### **Performance Comparison**

Mechanism	Resolution (ps)	Fluctuation (Process Var.) (%)	Fluctuation (Temp. Var.) (%)
Inverter-based	57	±4	±14
Buffer-based	36	±2	±12